Notice of References Cited Application/Control No. 10/605,653 Examiner Jason M. Han Applicant(s)/Patent Under Reexamination YU ET AL. Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,561,663	05-2003	Adachi et al.	362/616
	В	US-			
	С	US-			
	D	US-			
	Е	US-			
	I.	US-			
	G	US-			
	Н	US-			
	_	US-			
	٦	US-			
	K	US-			
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP0694920A	04-1994	Japan	Konno Teruaki	G02B 6/00
	0					
	Р					
	Q					
	R					
	s					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
	U					
	V					
	w					
	x					

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.